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1000		Exec	cutive M	ember:	CN	IES				Pate: 01/08/2014		224
Components (includ	ing series and familie	e) eubr	mitted fo	r Evtens	ion of	Qualification	Annreval	•		0.00201,		33K
	Ing series and familie	5) SUDI	milled 10	Extens	iion or	Qualification	Approval					
ESCC COMPONENT NO.	VARIANTS		RAN	GE OF C	ОМР	ONENTS	В	BASED ON	)	TEST VEHICLE / S	COMPON	
5201/001	01, 02, 04, 05, 06, 07	T	O-18, L	CC3, LC	C3+1		2N248	14				
5201/002	01, 02, 04, 05, 11,	įτ	TO-18, LCC3, LCC3+1 2N2			2N222	2A		ID33150009Z0	İ		
5201/004	01, 02, 04, 05, 06, 07	Ī	TO-18, LCC3, LCC3+1			2N3700			ID33129002Z5 ID3320400101			
5201/019	01, 02, 04, 05, 08,	į.	O-18, L	CC3, LC		******	2N5551		*****	***************************************	İ	
5203/010 5203/016	04,05,06,07 06,07	T	O-257,S O257				2N515 BUX77		ID33203002Z0			
5207/002	03,06,12,15		O-77,LC	CC6	PAIN T		2N292	0A				
Component M	anufacturer	2	Loc	ation of I	Manuf	acturing Plant	(s)	3				4
STMicroelectronics		3	, rue de	Suisse E	3P419	9, 35041 Renr	nes Cede	ex	Date:	of original qualification ap 02/09/1996	proval:	
									Certif	icate Ref No. 233		
		5						6				7
ESCC Specifications Maintenance of quali		D	eviation sed:	s to LVT	testin	g and Detail S	pecificati	on		fication Extension Report ence and date:		
Generic: 5000	Issue: 3	N	lo 🗵	Yes		(supply de	etails in B	Вох	RNS/	AN/14-146-01/CE rev2 2	6/05/2014	
Detail(s): 5201/00 5201/00		D	eviation	from cur	rrent S	Specifications:						
5201/00								- 1				
5201/01												
5203/01 5203/01												
5207/00												
		N	0 🛛	Yes		(Supply d	etails)					
						10 54 KGS	90 1200		Seattle St.	A400 - 1 2000 2440 1 2 1		8
Summary of procurer Project Name	nent or equivalent tes Testing Leve		ts during	current LAT	validit		oport of the		olication I	(those to ESCC listed fir	S2 "90 A S0 L	
TAS	Testing Leve	1		LAI		1218A to 1				Quantity I	Delivered	
EBV						1218A to 1	1414A					
Alter Italy		1				1218A to 1	1414A		-			
CRISA EADS		1				1218A to 1	414A		+			
ND					12		5,000A 15,400					
PID changes since st	art of qualification			9	- C	urrent PID Ve	erified by:		- 2.3	CNES		10
None						100000000				me of Excutive Represen		
Minor* ⊠					R	ef No: 80	097046 (	generi	c) Rev	13 and 8124528 (specific	Bipolar) rev 8	
Major* □	*Provide details in bo	X:			-	sue:				Date:	30/05/2014	4
illine			-		I Ke	ev Date:						11
Current Manufacturing	g facilities surveyed b	y:	-			ESA & CNES			on	09/0	06/2010	
				(Nar	ne of	Executive Rep	resentati	ve)		(0	Date)	
Satisfactory:	Yes ⊠	1	No	□ <b>E</b>	xplain							
Report Reference:	QCS/LB/1004	101	7.50	_								

ESCC
Failure Analysis, DPA, NCCS a
Pef. No's and purposes:

Transistor Bipolar NPN low and high power Component title:

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	Executive Member:	CNES	Date:	01/08/2014	233K
					1
ailure Analysis, DPA, NCCS	available: Yes	No 🗵	(Supply data)		
f. No's and purposes:					
i, ite o una parposos.					
e undersigned hereby certifies on b	shalf of the ESCC Executive -	that the above info	rmation is correct: -		L
t the appropriate documentation ha	s been evaluated; - that full co	mpliance to all ES	CC requirements is eviden	ce	
cept as stated in box 15;) - that the ES as the responsible Executive M	ember for ESCC qualification s	tatus to be extend	led to the component(s) lis	ted herein.	merch
				JP. BUSSENO	
te: 08/08/2014			(S	ignature of the Executive (	
			<u> </u>		
ntinuation of Boxes above:					L

9		ES	C	C	
Non con	npliance	to ESC	C req	uireme	ents

Component title: Transistor Bipolar NPN low and high power

CNES

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Non compliance to ESCC	requirements:
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15

No.:	Specification	Paragraph	Non compliance
		,	
1			
		1	
	ì		
4			
		1	
- 1			

Additional tasks required to achieve full compliance for ESCC qualification or rationale for acceptability of noncompliance:

Executive Member:

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**Executive Manager Disposition** 

Application Approval: Yes No 

Action / Remarks:

PRODUCT TESTED FOR HERMETICITY PER MIL-STD-750E, TM 1071.8 ARE ESCC COMPLIANT AS EXPLAINED IN EEPN-2012-1 (SEE ESCIES)

Date:

Signature, ESA Representative



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Date: 01/08/2014 Executive Member: CNES

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

Tests conducted in compliance with:

ESCC 5000 generic specification; Chart F4 (for ESCC/QPL parts); or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

2N2222A Lot ID33150009Z0 DC1227A SOC3700HR Lot ID3320400101 DC1207A	Chart F4 sg2
SOC3700 Lot ID33129002Z5 DC1221A 2N5154EsyHRB Lot ID33203002Z0 DC1314A	Full Chart F4

Detail Specification reference:

Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	N° of Rejects	Comments if not performed. Comments on Rejection
	Mechanical shock	×	MIL-STD-750 TM2016	1314A 1221A	15 + 15	0	
	Vibration		MIL-STD-750 TM2056	1314A 1221A	15 + 15	0	
	Constant acceleration	$\boxtimes$	MIL-STD-750 TM2006	1314A 1221A	15 + 15	0	
group	Seal Fine leak Gross leak	$\boxtimes$	MIL-STD-750 TM1071	1314A 1221A	15 + 15	0	
Environmental/Mechanical Subgroup	Electrical Measurement	⊠	Intermediate and End- Point Electrical Measurements	1314A 1221A	15 + 15	0	
nanic	External Visual	×	ESCC Basic Spec 20500	1314A 1221A	15 + 15	0	
al/Mecl	Thermal shock		MIL-STD-750 TM1056	Click here to enter text			Only applicable to axial lead glass diodes
ment	Temperature Cycling	⋈	MIL-STD-750 TM1051	1314A 1221A	15 + 15	0	
viron	Moisture Resistance	×	MIL-STD-750 TM1021	1314A 1221A	15 + 15	0	
En	Seal Fine leak Gross leak	×	MIL-STD-750 TM1071	1314A 1221A	15 + 15	0	Company
	Electrical Measurement	×	Intermediate and End- Point Electrical Measurements	1314A 1221A	15 + 15	0	
	External Visual	×	ESCC Basic Spec 20500	1314A 1221A	15 + 15	0	
dno	Operating Life	×	ESCC 5000 Para. 8.19	1314A 1221A 1227A 1207A	15 + 15 + 15 + 40	0	
Endurance Subgroup	Electrical Measurement	×	Intermediate and End- Point Electrical Measurements	1314A 1221A 1227A 1207A	15 + 15 + 15 + 40	0	
nduran	Seal Fine leak Gross leak	Ø	MIL-STD-750 TM1071	1314A 1221A 1227A	15 + 15 + 15	0	
ш	External Visual Inspection	×	ESCC Basic Spec 20500	1314A 1221A 1227A	15 + 15 + 15	0	
22.250M	Permanence of Marking		ESCC Basic Spec 24800				Not applicable on Laser marking
bly up	Terminal Strength	×	ESCC 5000 Para. 8.18	1314A 1221A	5 + 5	0	
Assembly Capability Subgroup	Internal Visual		ESCC Basic Spec 20400	1314A 1221A	5 + 5	0	
SCS	Bond Strength	×	MIL-STD-750 TM 2037	1314A 1221A	3 + 5	0	
	Die Shear		MIL-STD-750 TM 2017	1314A 1221A	3 + 3	0	



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Ch art F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	N° of Rejects	Comments if not performed. Comments on Rejection
la .							
Tests							
A							



Box 2; 3 and 4

Box 9

**Box 11** 

Box 12

Box 13

**Box 14** 

#### APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

Component title:

Transistor Bipolar NPN low and high power

Executive Member:

CNES

Date: 01/08/2014

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# NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL

Form heading	shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.
Box 1	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle reter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a refer in the component tested).

designation given in the detail specification as base on, - under rest verifice enter entre an EGGG code of the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross As per QPL entry; otherwise, an explanation of the changes must be supplied.

Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests Box 5 reported were performed. If the specifications are different from those current on the date of the application, see Box 6.

Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of Box 6 deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.

Box 7 Must reference the report(s) supplied in support of the application.

Box 8 Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in

If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.

Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be Box 10 arranged as close as possible to the required date of extension.

> This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.

Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced

Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive

To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.

**Box 15** Fill in Table as requested

**Box 16** Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.

**Box 17** All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.

**Box 18** Fill in Table as requested

**Box 19** Confidential Details of PID changes including those of a confidential nature, shall be provided.

State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance **Box 20** shall be sequentially numbered. If relevant state 'None'

Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted **Box 21** by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.

**Box 22** Additional Comments